10/565631 **IAP20 Rec'd PCT/FTO 24 JARY 2005**

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Jerome DOURET et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed January 24, 2006

Examiner

METHOD FOR CALIBRATING AT LEAST TWO VIDEO CAMERAS RELATIVELY TO EACH OTHER FOR STEREOSCOPIC FILMING AND DEVICE THEREFOR

INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

January 24, 2006

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

II. COPIES

Copies	of	the U	.s.	patents	or p	ublications	are	not	submitted
since	the	USPTO	has	waived	thei	r submission	for	app	olications
filed	afte	r June	30,	2003.					

- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

Docket No. 0581-1014

III.	CONC)	SE EX	Teast one box) THE RELEVANCE PORTURN 24 JAN 2006
	a.		DOCUMENTS IN THE ENGLISH LANGUAGE
			The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.
	b.		DOCUMENTS NOT IN THE ENGLISH LANGUAGE
			A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:
	c.	\boxtimes	FOREIGN SEARCH REPORT OR ACTION
			An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).
	d.		OTHER
			The following additional information is provided for the Examiner's consideration.
			<u>FEES</u>
concu there	This urrent efore,	:ly	ormation Disclosure Statement is being filed with the filing of a new patent application; see is required.
is re	If T equest	he Ex	aminer has any questions concerning this IDS, he/she contact the undersigned.
			Respectfully submitted,
			Benoit Castel Benoit Castel, Reg. No. 35,041 745 South 23 rd Street
			Arlington, VA 22202 Telephone (703) 521-2297 Telefax (703) 685-0573 (703) 979-4709
BC/y	c		
Encl	osures	3:	✓ Form PTO-1449(s)☐ Documents✓ Foreign Search Report
			Other:

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INFORMATION DISCLOSURE CITATION	Attorney Docket No.: 0581-1014	NEW NATIONAL PH		
IN AN APPLICATION	Applicant: Jerome DOURET et al.			
(Use several sheets if necessary)	Filing Date:	Group Art Unit:		

| January 24, 2006 **U.S. PATENT DOCUMENTS Document Number** Date Examiner Name Class Subclass Filing date Initial (if appropriate) **FOREIGN PATENT DOCUMENTS** Examiner **Document Number** Date Class Translation Country Subclass Initial Yes No /Y.A./ WO 02/50770 6/27/2002 INTERNATIONAL /Y.A./ 1 089 054 4/4/2001 **EUROPE** OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) **EXAMINER:** DATE CONSIDERED /Yogesh Aggarwal/ 02/26/2009

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

^{*} English language abstract provided for the Examiner's convenience